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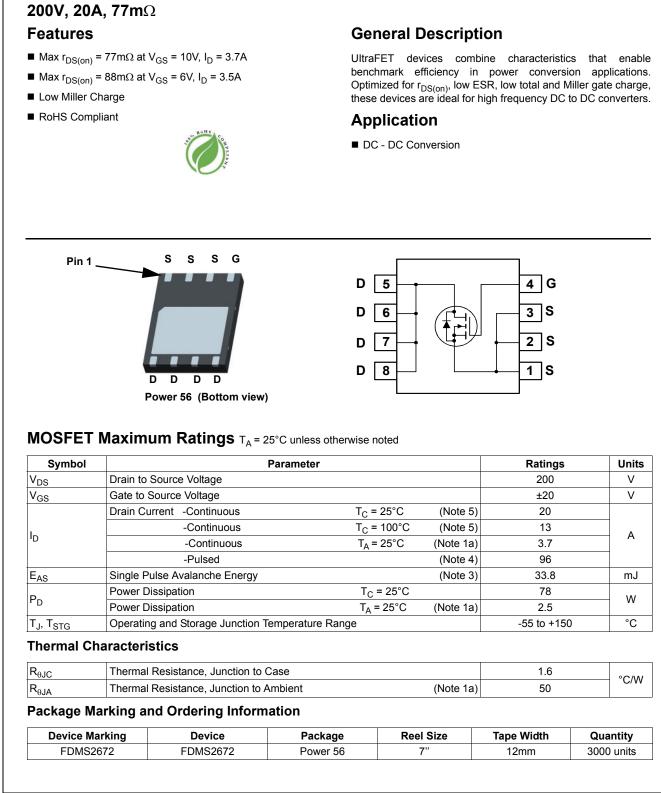


ON Semiconductor®

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October 2015

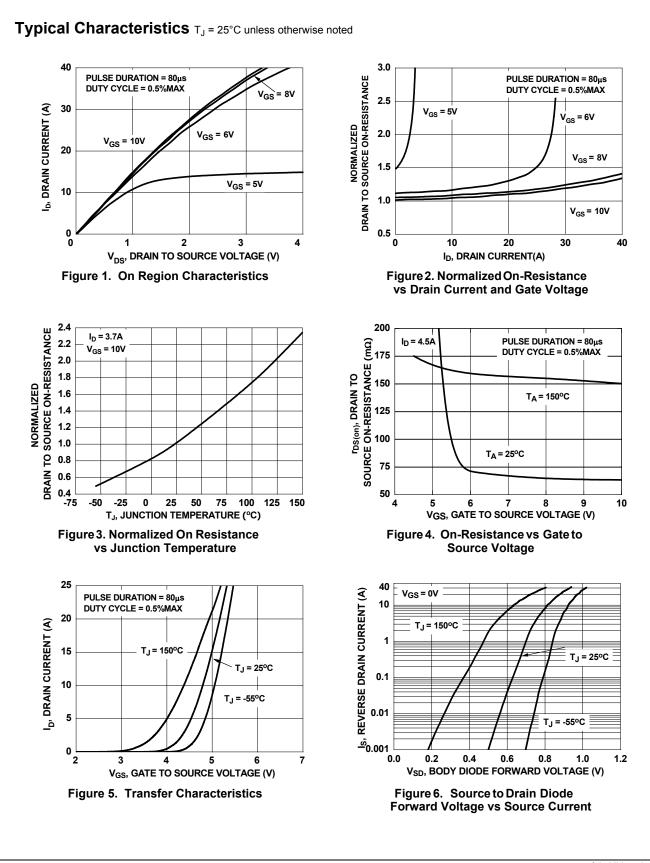
FAIRCHILD

FDMS2672

N-Channel UltraFET Trench MOSFET

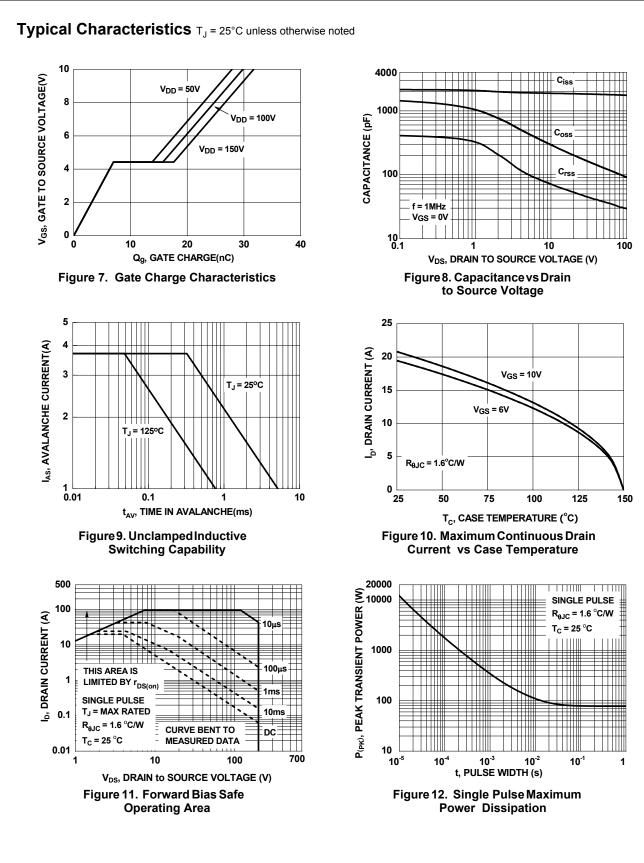
DSDescriptionDSDSDS I_{GSS} Gate to Source Leakage Current $V_{GS} = \pm 20V, V_{DS} = 0V$ $\pm \pm 20V, V_{DS} = 0V$ On Characteristics $V_{GS(th)}$ Gate to Source Threshold Voltage $V_{GS} = V_{DS}, I_D = 250\mu A$ 2 3.1 $\Delta V_{GS(th)}$ Gate to Source Threshold Voltage $I_D = 250\mu A, referenced to 25^{\circ}C$ -10 $T_{DS(on)}$ Drain to Source On Resistance $V_{GS} = 10V, I_D = 3.7A$ 64 $T_{SS(on)}$ Drain to Source On Resistance $V_{DS} = 10V, I_D = 3.7A$ 14 Optimize CharacteristicsOptimize Characteristics C_{iss} Input Capacitance $V_{DS} = 100V, V_{GS} = 0V,$ 1740 23 C_{iss} Input Capacitance $V_{DS} = 100V, V_{GS} = 0V,$ 1740 23	V V MV/°(1 μA ±100 nA 4 V mV/°(777 88 mΩ	210		I_D = 250µA, referenced to 25°C V_{DS} = 160V V_{GS} = ±20V, V_{DS} = 0V	Drain to Source Breakdown Voltage Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current Gate to Source Leakage Current	V _{DSS} BV _{DSS} ∆T _J SS
BV_{DSS} Drain to Source Breakdown Voltage $I_D = 250\mu A, V_{GS} = 0V$ 200 ΔBV_{DSS} ΔT_J Breakdown Voltage Temperature Coefficient $I_D = 250\mu A, referenced to 25^{\circ}C$ 210 I_{DSS} Zero Gate Voltage Drain Current $V_{DS} = 160V$ 1 I_{DSS} Gate to Source Leakage Current $V_{GS} = \pm 20V, V_{DS} = 0V$ $\pm \pm 20V, V_{DS} = 0V$ On Characteristics $V_{GS(th)}$ Gate to Source Threshold Voltage $V_{GS} = V_{DS}, I_D = 250\mu A$ 2 3.1 $\Delta V_{GS(th)}$ Gate to Source Threshold Voltage $I_D = 250\mu A, referenced to 25^{\circ}C$ -10 $\Delta V_{GS(th)}$ Gate to Source On Resistance $V_{GS} = 10V, I_D = 3.7A$ 64 7 $r_{DS(on)}$ Drain to Source On Resistance $V_{GS} = 10V, I_D = 3.7A$ 64 7 g_{FS} Forward Transconductance $V_{DS} = 10V, I_D = 3.7A$ 14 Dynamic Characteristics C_{iss} Input Capacitance $V_{DS} = 100V, V_{GS} = 0V,$ 1740 23 C_{iss} Input Capacitance $V_{DS} = 100V, V_{GS} = 0V,$ 1740 23	0 mV/°0 1 μA ±100 nA 4 V mV/°0 77 88 mΩ	3.1		I_D = 250µA, referenced to 25°C V_{DS} = 160V V_{GS} = ±20V, V_{DS} = 0V	Drain to Source Breakdown Voltage Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current Gate to Source Leakage Current	V _{DSS} BV _{DSS} ∆T _J SS
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On Characteristics V_{GS(th)} Gate to Source Threshold Voltage $V_{GS} = V_{DS}$, $I_D = 250 \mu A$ 2 3.1 $\Delta V_{GS(th)}$ Gate to Source Threshold Voltage Temperature Coefficient $I_D = 250 \mu A$, referenced to 25° C -10 $r_{DS(on)}$ Drain to Source On Resistance $V_{GS} = 10V$, $I_D = 3.7A$ 64 7 g_{FS} Forward Transconductance $V_{DS} = 10V$, $I_D = 3.7A$ 14 14 Optimize Characteristics C_{iss} Input Capacitance $V_{DS} = 100V$, $V_{GS} = 0V$, 1740 23 C_{iss} Input Capacitance $V_{DS} = 100V$, $V_{GS} = 0V$, 1740 23	4 V mV/°0 77 88 mΩ		2		<u> </u>	
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$ \begin{array}{c c} \Delta V_{GS}(th) \\ \hline \Delta T_J \end{array} & \hline \text{Gate to Source Threshold Voltage} \\ \hline \text{Temperature Coefficient} \end{array} & I_D = 250 \mu\text{A}, \text{ referenced to } 25^\circ\text{C} \end{array} & \begin{array}{c} -10 \\ \hline \text{Temperature Coefficient} \end{array} \\ \hline r_{DS(on)} \end{array} & \hline \text{Drain to Source On Resistance} \end{array} & \begin{array}{c} V_{GS} = 10\text{V}, \ I_D = 3.7\text{A} \\ \hline V_{GS} = 6\text{V}, \ I_D = 3.5\text{A} \\ \hline V_{GS} = 10\text{V}, \ I_D = 3.7\text{A} \\ \hline V_{GS} = 10\text{V}, \ I_D = 3.7\text{A} \\ \hline V_{GS} = 10\text{V}, \ I_D = 3.7\text{A} \\ \hline \text{Source Characteristics} \end{array} \\ \hline \begin{array}{c} \text{Dynamic Characteristics} \\ \hline C \\ \hline C \\ \hline \end{array} & \begin{array}{c} 1740 \\ \hline 23 \\ \hline \end{array} \\ \hline \end{array} \\ \hline \end{array} $	mV/°0 77 88 mΩ		2	(1 - 1) = 250		n Chara
$ \begin{array}{c c} \underline{\Delta V_{GS}} \\ \underline{\Delta T_J} \\ \hline \Delta T_J \\ \hline \Delta$	77 88 mΩ	-10		$V_{GS} = V_{DS}$, $I_D = 250 \mu A$	Gate to Source Threshold Voltage	GS(th)
ΔT_{J} Temperature Coefficient $I_{D} = 230 \mu$, referenced to 25 C -10^{-1} $r_{DS(on)}$ Drain to Source On Resistance $V_{GS} = 10V, I_{D} = 3.7A$ 647 $V_{GS} = 6V, I_{D} = 3.5A$ 698 $V_{GS} = 10V, I_{D} = 3.7A T_{J} = 125^{\circ}C$ 1291 g_{FS} Forward Transconductance $V_{DS} = 10V, I_{D} = 3.7A$ 14Dynamic Characteristics C_{iss} Input Capacitance $V_{DS} = 100V, V_{GS} = 0V,$ 174023 C_{iss} Output Capacitance $V_{DS} = 100V, V_{GS} = 0V,$ 951	77 88 mΩ	-10			-	
$r_{DS(on)}$ Drain to Source On Resistance $V_{GS} = 6V, I_D = 3.5A$ 6969 g_{FS} Forward Transconductance $V_{DS} = 10V, I_D = 3.7A T_J = 125^{\circ}C$ 1291 Dynamic Characteristics C_{iss} Input Capacitance $V_{DS} = 100V, V_{GS} = 0V,$ 174023 C_{iss} Output Capacitance $V_{DS} = 100V, V_{GS} = 0V,$ 174023	88 mΩ			$I_D = 250 \mu A$, referenced to 25 C	Temperature Coefficient	
$V_{GS} = 10V, I_D = 3.7A T_J = 125^{\circ}C$ 1291 g_{FS} Forward Transconductance $V_{DS} = 10V, I_D = 3.7A$ 14 Oynamic Characteristics C_{iss} Input Capacitance $V_{DS} = 100V, V_{GS} = 0V,$ 174023 C_{iss} Output Capacitance $V_{DS} = 100V, V_{GS} = 0V,$ 174023		64				
g_{FS} Forward Transconductance $V_{DS} = 10V$, $I_D = 3.7A$ 14 Dynamic Characteristics C_{iss} Input Capacitance $V_{DS} = 100V$, $V_{GS} = 0V$,174023 C_{iss} Output Capacitance $V_{DS} = 100V$, $V_{GS} = 0V$,9511	156				Drain to Source On Resistance	S(on)
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$C_{iss} \qquad \text{Input Capacitance} \qquad V_{DS} = 100V, V_{GS} = 0V, \qquad 1740 \qquad 23$	S	14		$V_{\rm DS} = 10V, I_{\rm D} = 3.7A$	Forward Transconductance	S
$V_{DS} = 100V, V_{GS} = 0V,$ 95 11					Characteristics	ynamic
$V_{DS} = 100V, V_{GS} = 0V,$ 95 11) 2315 pF	1740			Input Capacitance	ss
	125 pF	95		$v_{DS} = 1000, v_{GS} = 00,$ f = 1MHz	Output Capacitance	
	45 pF	30			Reverse Transfer Capacitance	rss
	5 Ω	1	0.1		Gate Resistance	
Switching Characteristics					a Characteristics	witchin
	34 ns	22			-	
$V_{} = 100V_{} = 3.74$	22 ns			V_{DD} = 100V, I _D = 3.7A V_{GS} = 10V, R _{GEN} = 6Ω		(on)
$V_{GS} = 10V, R_{GEN} = 6\Omega$	57 ns					
	20 ns					(0ff)
	20 113	-		$V_{00} = 0V to 10V V_{0} = 100V$		
	42 nC			$V_{\text{GS}} = 100 \text{V}$		
QgGate to Drain "Miller" Charge1QgdGate to Drain "Miller" Charge8	42 nC	7		ID = 3.7A	-	qs
	nC	7			Gate to Drain "Miller" Charge	
Duain Cauraa Diada Characteriatian					_ I	gd
	nC nC	8		(1 - 0)(1 - 2.74) (Note 2)	urce Diode Characteristics	^{gd} rain-So
V_{SD} Source to Drain Diode Forward Voltage $V_{GS} = 0V$, $I_S = 3.7A$ (Note 2) 0.8 1	nC nC 1.2 V	8		V _{GS} = 0V, I _S = 3.7A (Note 2)	urce Diode Characteristics Source to Drain Diode Forward Voltage	gd rain-So
t _{rr} Reverse Recovery Time I _F = 3.7A, di/dt = 100A/us	nC nC nC 1.2 V 105 ns	8 0.8 70			urce Diode Characteristics Source to Drain Diode Forward Voltage Reverse Recovery Time	rain-So
	42				Gate to Drain "Miller" Charge	

Pulse Test: Pulse Width < 300µs, Duty cycle < 2.0%.
 E_{AS} of 33.8mJ is based on starting T_J = 25 C, L = 3mH, I_{AS} = 4.75A, V_{DD} = 25V, V_{GS} = 10V.
 Pulsed Id please refer to Fig 11 SOA graph for more details.
 Computed continuous current limited to Max Junction Temperature only, actual continuous current will be limited by thermal & electro-mechanical application board design.

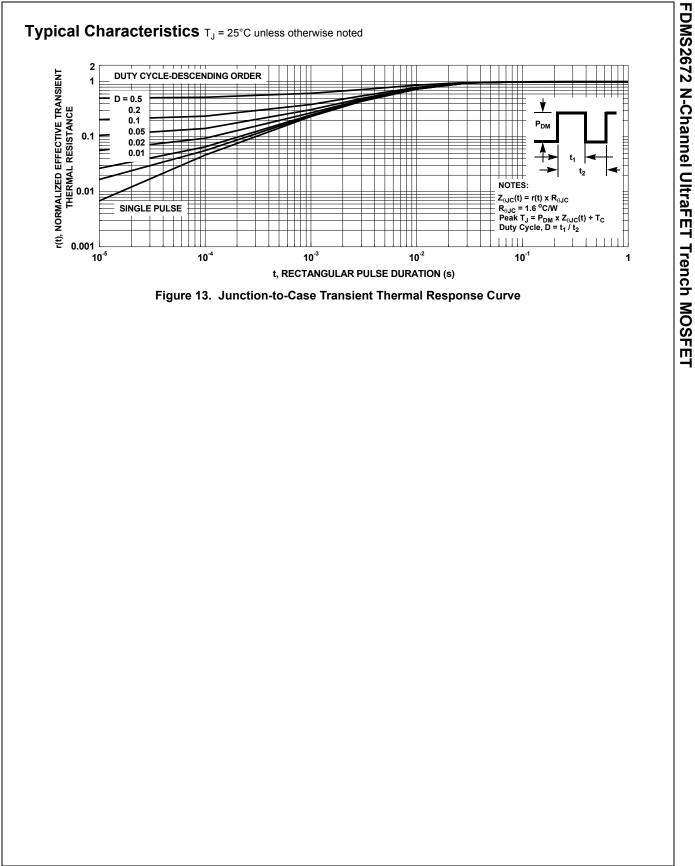


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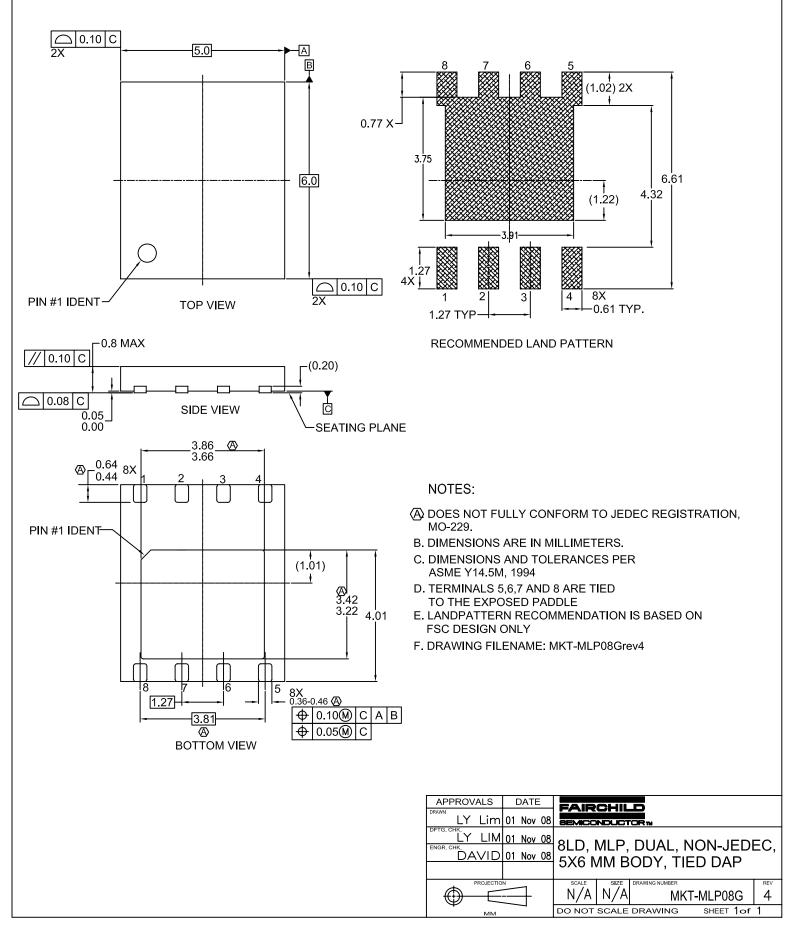




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	REVISIONS					
NBR	DESCRIPTION	DATE	NAME/SITE			
1	RELEASE TO DOCUMENT CONTROL	090305	David/FSPM			
2	REVISE TO CORRECT DAP SIZE	080605	David/FSPM			
3	I) REVISE TO CORRECT PKG THK					
	II) REVISE THE PKG PROFILE TOLERANCE	210306	CK/FSPM			
4	ADD IN LEAD LENGTH FOR LAND PATTERN	220908	LY/FSPM			



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